

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/713,468	KNIERIM ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Hai L. Nguyen	2816

SEARCHED			
Class	Subclass	Date	Examiner
331	16,18,25, 1A,1R, DIG.2	4/20/2005	HLN
327	47,115		
	117,147		
	156,167		
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375	373,375	4/21/2005	
	376		
377	48	V	V
Update	Search	10/14/2005	HLN
Update	Search	1/23/2006	HLN

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
See	Printout	1/23/2006	HLN